

The SIR-3400 Mid-Infrared Fiber Optic Analyzer is a first for optical-based infrared spectrometers. This SIR scanning spectrometer collects spectral data over the 1-3.4 µm wavelength range and features a fiber-based system for rapid spectral scans over its entire range. It can also provide real-time data from several discrete wavelengths.

The SIR-3400 uses a single point detector and a high angular resolution-tunable grating system. The zero-backlash mechanical design provides superior accuracy and repeatability. This combination, along with an innovative 24-bit A/D converter, provides high spectral resolution and very high signal-to-noise data.

An optional filter wheel provides optical order sorting of diffracted orders.

The SIR-3400 is designed with a rugged aluminum housing that is robust enough to withstand the rigors of chemical processing applications.

The USB 2.0-compliant interface provides fast data transfers and our included software can be used to control all of the SIR-3400's functions as well as analyze data.

## **Specifications**

Range: 1-3.4 μm

Detector: InAs with 3 stage cooler
Diffraction grating: 300 lines/mm 2.0 µm blaze

Optical design: Czerny-Turner F/3

Slits available:  $10~\mu m$ ,  $50~\mu m$ ,  $100~\mu m$ ,  $200~\mu m$ ,  $500~\mu m$  Optical input: SMA-905/906 with optional lensed input

Analog resolution: 24 bits 16,777,216 counts

Triggering options: Internal and external synchronization, pulse width control and phase delay

Additional digital outputs: 2 channel selectable 3.3V/5V output Additional digital inputs: 2 channels 3.3V/5V compatible inputs

Grating steps in range: 16,800
Step accuracy: +/- 10 steps
Data interface: USB 2.0

Scan time: As quick as 20 seconds

Resolution based on 10  $\mu m$  .22 nm optical slits: 50  $\mu m$  1.1 nm 100  $\mu m$  2.22 nm 200  $\mu m$  5 nm

200 μm 5 nm 500 μm 11 nm

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